



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AO4402G**  
**20V N-Channel MOSFET**

### General Description

- Trench Power MOSFET technology
- Low  $R_{DS(ON)}$
- RoHS and Halogen-Free Compliant

### Product Summary

$V_{DS}$	20V
$I_D$ (at $V_{GS}=4.5V$ )	20A
$R_{DS(ON)}$ (at $V_{GS}=4.5V$ )	< 5.9mΩ
$R_{DS(ON)}$ (at $V_{GS}=2.5V$ )	< 7.3mΩ

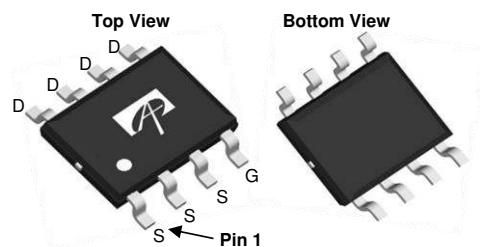
### Applications

- DC/DC Converters in Computing, Servers, and POL
- Battery protection switch

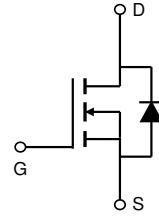
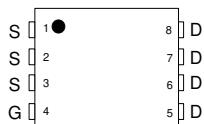
100% UIS Tested  
100%  $R_g$  Tested



SOIC-8



Top View



### Orderable Part Number

### Package Type

### Form

### Minimum Order Quantity

AO4402G	SO-8	Tape & Reel	3000
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### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	20	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Continuous Drain Current	$I_D$	20	A
$T_A=70^\circ C$		15	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	80	
Avalanche Current <sup>C</sup>	$I_{AS}$	40	A
Avalanche energy $L=0.1\text{mH}$ <sup>C</sup>	$E_{AS}$	80	mJ
Power Dissipation <sup>B</sup>	$P_D$	3.1	W
$T_A=25^\circ C$		2.0	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	31	40	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup> Steady-State		59	75	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	16	24	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	20			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=20\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$			$\pm 100$	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.45	0.85	1.25	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=4.5\text{V}, I_D=20\text{A}$ $T_J=125^\circ\text{C}$		4.9	5.9	$\text{m}\Omega$
		$V_{GS}=2.5\text{V}, I_D=18\text{A}$		6.3	7.6	
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		100		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.6	1	V
$I_S$	Maximum Body-Diode Continuous Current				5	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=10\text{V}, f=1\text{MHz}$		3300		pF
$C_{oss}$	Output Capacitance			485		pF
$C_{rss}$	Reverse Transfer Capacitance			370		pF
$R_g$	Gate resistance	$f=1\text{MHz}$	1.2	2.4	3.6	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(4.5\text{V})$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, I_D=20\text{A}$		31	45	nC
$Q_{gs}$	Gate Source Charge			5.2		nC
$Q_{gd}$	Gate Drain Charge			8		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=10\text{V}, R_L=0.5\Omega, R_{\text{GEN}}=3\Omega$		7.5		ns
$t_r$	Turn-On Rise Time			15		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			72		ns
$t_f$	Turn-Off Fall Time			21		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$		17		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$		30		nC

A. The value of  $R_{iJA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{ C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{ C}$ , using  $\leq 10\text{s}$  junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{ C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{ C}$ .

D. The  $R_{iJA}$  is the sum of the thermal impedance from junction to lead  $R_{iJL}$  and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using  $<300\mu\text{s}$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{ C}$ . The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

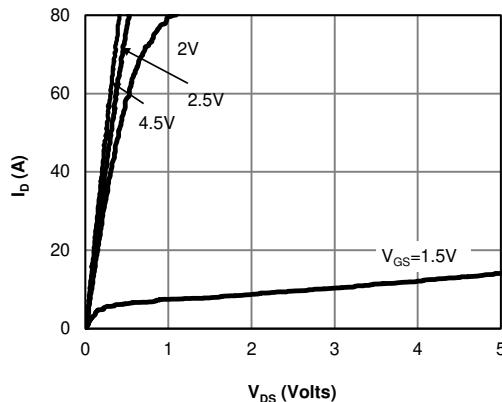


Figure 1: On-Region Characteristics (Note E)

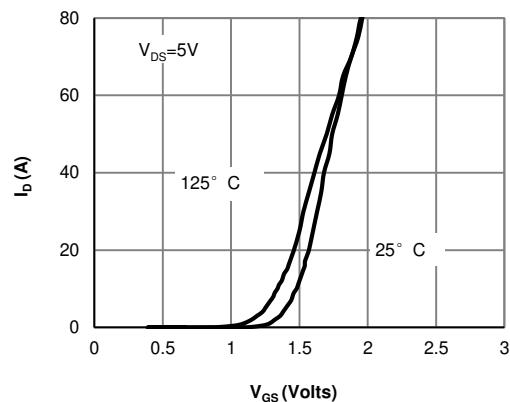


Figure 2: Transfer Characteristics (Note E)

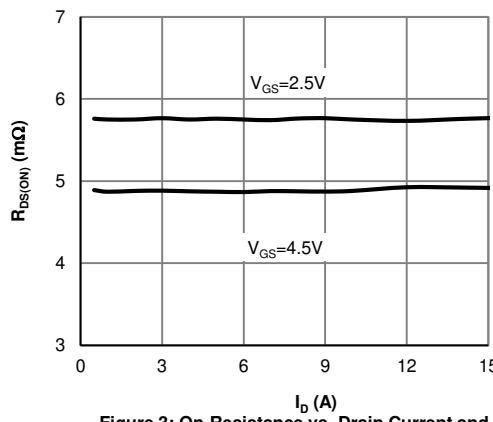


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

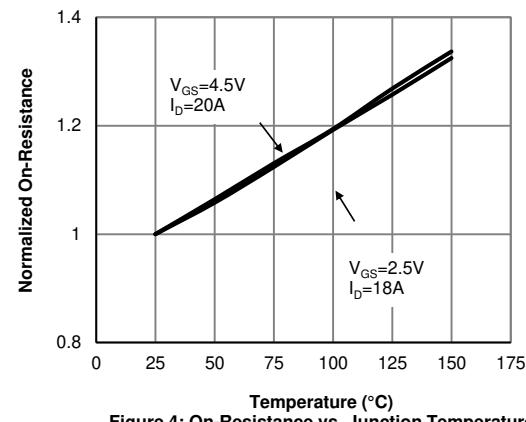


Figure 4: On-Resistance vs. Junction Temperature (Note E)

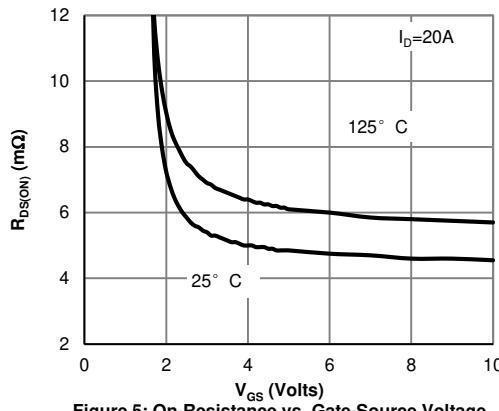


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

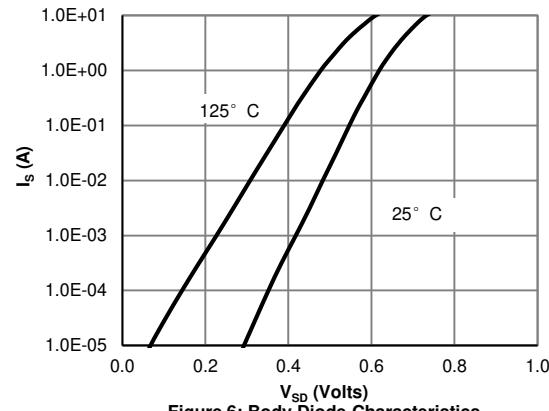


Figure 6: Body-Diode Characteristics (Note E)



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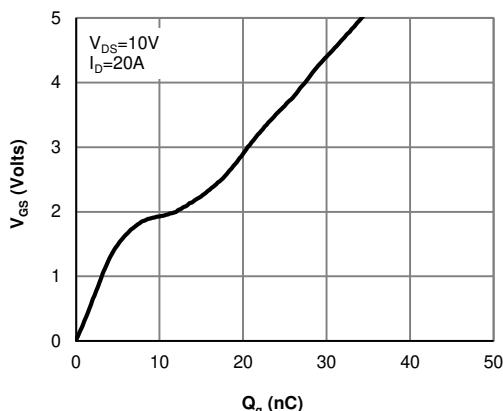


Figure 7: Gate-Charge Characteristics

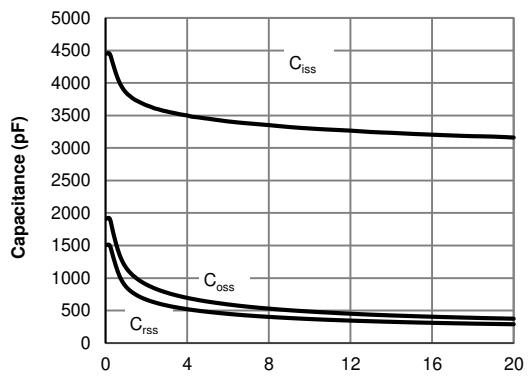


Figure 8: Capacitance Characteristics

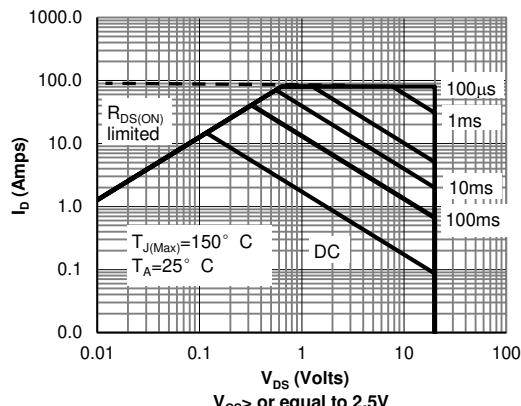


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

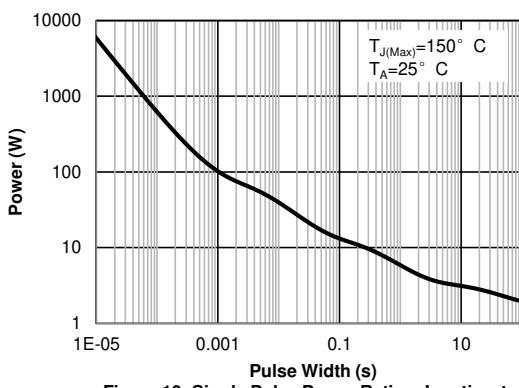


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

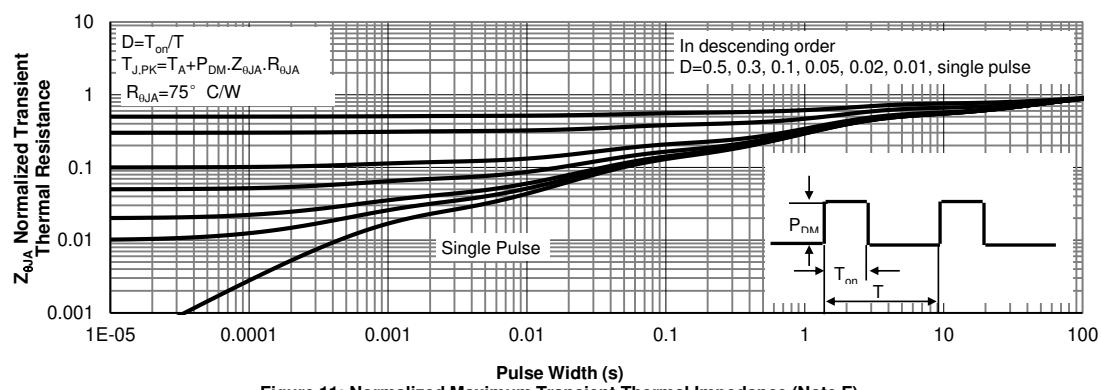


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



Figure A: Gate Charge Test Circuit & Waveforms

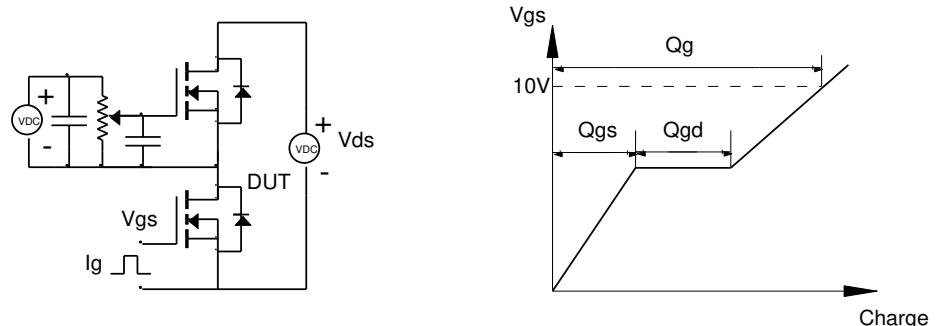


Figure B: Resistive Switching Test Circuit & Waveforms

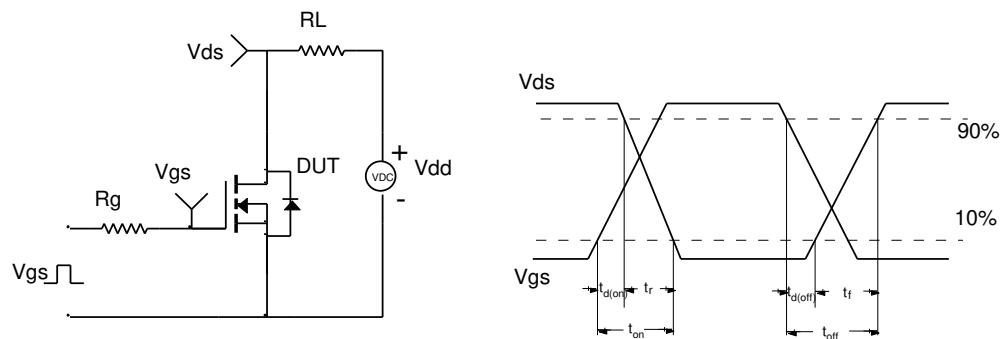


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

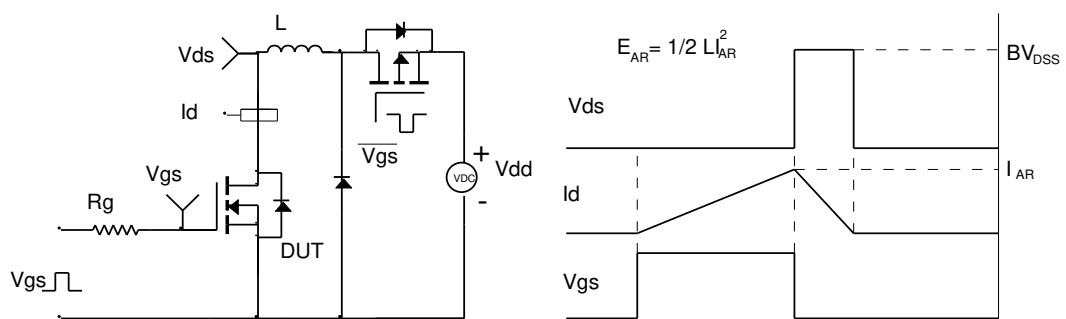


Figure D: Diode Recovery Test Circuit & Waveforms

